



PATENT

Case Docket No. OPTRES.026C2

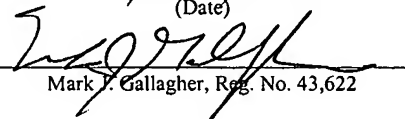
Date: March 23, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Hoffman, et al.  
Appl. No. : 10/759,699  
Filed : January 19, 2004  
For : CORRECTION OF  
BIREFRINGENCE IN CUBIC  
CRYSTALLINE OPTICAL  
SYSTEMS  
Examiner : Unknown  
Group Art Unit : Unknown

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3/23/04  
(Date)

  
Mark J. Gallagher, Reg. No. 43,622

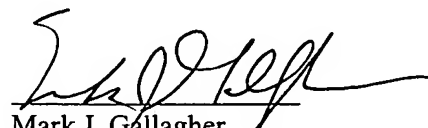
TRANSMITTAL LETTER

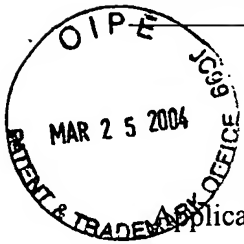
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed for filing in the above-identified application are:

- (X) An Information Disclosure Statement.
- (X) A PTO Form 1449 with sixty six (66) references listed with thirty seven (37) enclosed.
- (X) The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.
- (X) Return prepaid postcard.

  
Mark J. Gallagher  
Registration No. 43,622  
Attorney of Record  
Customer No. 20,995  
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## INFORMATION DISCLOSURE STATEMENT

Applicant	:	Hoffman, et al.
App. No.	:	10/759,699
Filed	:	January 19, 2004
For	:	CORRECTION OF BIREFRINGENCE IN CUBIC CRYSTALLINE OPTICAL SYSTEMS
Examiner	:	Unknown
Group Art Unit	:	Unknown

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

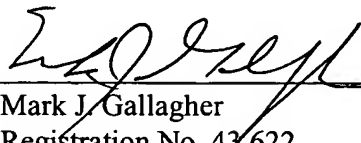
Enclosed is form PTO-1449 listing sixty six (66) references. Some of these references are cited in U.S. patent application No. 10/071,375, filed February 7, 2002, which is the parent of this continuation application, and is relied upon for an earlier filing date under 35 U.S.C. § 120. Copies of these are not enclosed pursuant to 37 C.F.R. § 1.98(d).

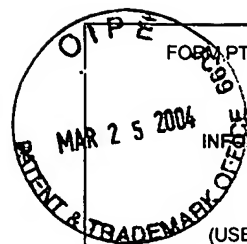
This Information Disclosure Statement is being filed before the receipt of a first Office Action on the merits, and presumably no fee is required in accordance with 37 C.F.R. § 1.97(b)(3). If a first Office Action on the merits was mailed before the mailing date of this Statement, the Commissioner is authorized to charge the fee set forth in 37 C.F.R. § 1.17(p) to Deposit Account No. 11-1410.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: 3/23/04

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FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
OPTRES.026C2APPLICATION NO.  
10/759,699INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT  
Hoffman, et al.FILING DATE  
January 19, 2004GROUP  
Unknown

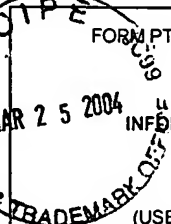
## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	1	3,758,201	09/11/73	MacNeille			
	2	4,239,329	12/16/80	Matsumoto			
	3	4,534,649	08/13/85	Downs			
	4	4,576,479	03/18/86	Downs			
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	6	5,537,260	07/16/96	Williamson			
	7	6,081,382	06/27/00	Omura			
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	18	2001/0026006	10/04/02	Noble, et al.			
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	21	2003/0025894	02/2003	Owa, et al.			
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	26	2003/0086156	05/08/03	McGuire, Jr.			
	27	2003/0086171	05/2003	McGuire, Jr.			

EXAMINER

DATE CONSIDERED

\*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

 FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. OPTRES.026C2	APPLICATION NO. 10/759,699
	APPLICANT Hoffman, et al.	
	FILING DATE January 19, 2004	GROUP Unknown

## U.S. PATENT DOCUMENTS

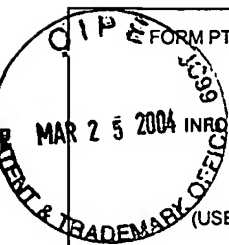
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	28	2003/0168597	09/11/03	Webb, et al.			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	29	EP 0 828 172	03/11/98	European Patent Office				
	30	JP 2000-331927	11/30/00	Japan				
	31	EP 1 063 684	12/27/00	European Patent Office				
	32	EP 1 115 019	07/11/01	European Patent Office				
	33	EP 1 139 138	10/04/01	European Patent Office				
	34	WO 02/093209	11/21/02	PCT				
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	36	WO 02/099500	12/12/02	PCT				
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	39	WO 03/009050	01/30/03	PCT				
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	41	Rudolf Kingslake, <i>Lens Design Fundamentals</i> , 1978, pp. 320-321, Academic Press, Inc., San Diego, California
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	43	Shiraishi, et al., "Current Status of Nikon's Investigation on CaF <sub>2</sub> Intrinsic Birefringence", International-SEMATECH . Calcium Fluoride Birefringence Workshop, July 18, 2001, pp. 1-15
	44	Burnett, et al., "Intrinsic Birefringence in Calcium Fluoride", National Institute of Standards and Technology, Gaithersburg, Maryland 20899, submitted for publication to Physical Review Letters (May 11, 2001), pp. 1-12
	45	Burnett, et al., "Minimizing spatial-dispersion-induced birefringence in crystals for precision optics by using mixed crystals of materials with t opposite sign of the birefringence", National Institute of Standards and Technology, Gaithersburg, Maryland 20899, <a href="http://physics.nist.gov/Divisions/Div842/Gp3/DUVMatChar/birefring.nt">http://physics.nist.gov/Divisions/Div842/Gp3/DUVMatChar/birefring.nt</a> (July 12, 2001), pp. 1-3
	46	U.S. Provisional Patent Application 60/306,206, filed July 18, 2001 which is a priority document for WO 03/009050

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	APPLICANT Hoffman, et al.	
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EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	47 U.S. Provisional Patent Application 60/308,844, filed August 1, 2001 (Japanese Language)
	48 English translation of Provisional Application No. 60/308,844, filed August 1, 2001 (filed in USPTO on October 23, 2002)
	49 Burnett, et al., "Intrinsic birefringence in calcium fluoride and barium fluoride", Physical Review B, Vol. 64, May 14, 2001, pp. 241102-1-241102-4
	50 Burnett, et al., "Intrinsic Birefringence in 157 nm Materials", Proceedings of the International Symposium on 157NM Lithography, Dana Point, CA, May 15, 2001, XP002218849, pp. 1-13
	51 Burnett, et al., "Intrinsic Birefringence in 157 nm Materials", Proc 2 <sup>nd</sup> , Intl. Sump on 157 nm Lithography, 2001, pp. 1-13, International SEMATECH, Austin, Texas
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	53 D. Krämer, "Intrinsic Birefringence in CaF <sub>2</sub> " at CaF <sub>2</sub> Birefringence Worksho[, Intl SEMATECH, July 18, 2001, pp. 1-9
	54 Morton, et al., "Testing Optical Damage for 157 nm Lithography", Semiconductor International, <a href="http://www.e-insite.net/semiconductor/index.asp?layout=article&amp;stt">http://www.e-insite.net/semiconductor/index.asp?layout=article&amp;stt</a> (February 2002)
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	57 Yeh, et al., "Optics of Liquid Crystal Displays", John Wiley & Sons, Inc., New York, 1999, pp. 380-385
	58 U.S. Patent Application 10/178,601, filed June 20, 2002 (OPTRES.002A)
	59 U.S. Patent Application 10,178,937, filed June 20, 2002 (OPTRES.003A)
	60 U.S. Patent Application 10/178,621, filed June 20, 2002 (OPTRES.004A)
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	64 U.S. Patent Application 10/331,103, filed December 26, 2002 (OPTRES.013A)
	65 U.S. Patent Application 10/371,266, filed February 20, 2003 (OPTRES.026C1)
	66 U.S. Patent Application 10/371,269, filed February 20, 2003 (OPTRES.026DV1)

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